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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### **Details**

Product Status	Active
Number of LABs/CLBs	42960
Number of Logic Elements/Cells	549888
Total RAM Bits	23298048
Number of I/O	1200
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-FCBGA (42.5x42.5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc6vlx550t-2ffg1760c">https://www.e-xfl.com/product-detail/xilinx/xc6vlx550t-2ffg1760c</a>

Table 3: DC Characteristics Over Recommended Operating Conditions (1)(2)

Symbol	Description	Min	Typ	Max	Units
$V_{DRINT}$	Data retention $V_{CCINT}$ voltage (below which configuration data might be lost)	0.75	—	—	V
$V_{DRI}$	Data retention $V_{CCAUX}$ voltage (below which configuration data might be lost)	2.0	—	—	V
$I_{REF}$	$V_{REF}$ leakage current per pin	—	—	10	$\mu A$
$I_L$	Input or output leakage current per pin (sample-tested)	—	—	10	$\mu A$
$C_{IN}^{(3)}$	Die input capacitance at the pad	—	—	8	pF
$I_{RPU}$	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 2.5V$	20	—	80	$\mu A$
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.8V$	8	—	40	$\mu A$
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.5V$	5	—	30	$\mu A$
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.2V$	1	—	20	$\mu A$
$I_{RPD}$	Pad pull-down (when selected) @ $V_{IN} = 2.5V$	3	—	80	$\mu A$
$I_{BATT}$	Battery supply current	—	—	150	nA
$n$	Temperature diode ideality factor	—	1.0002	—	n
$r$	Series resistance	—	5	—	$\Omega$

**Notes:**

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

## Important Note

Typical values for quiescent supply current are specified at nominal voltage, 85°C junction temperatures ( $T_j$ ). Xilinx recommends analyzing static power consumption at  $T_j = 85^\circ\text{C}$  because the majority of designs operate near the high end of the commercial temperature range. Quiescent supply current is specified by speed grade for Virtex-6 devices. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified in Table 4.

**Table 4: Typical Quiescent Supply Current**

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) <sup>(2)</sup>	-1L (C)	-1L (I) <sup>(1)</sup>	
$I_{CCINTQ}$	Quiescent $V_{CCINT}$ supply current	XC6VLX75T	927	927	927	N/A	656	741	mA
		XC6VLX130T	1563	1563	1563	N/A	1102	1245	mA
		XC6VLX195T	2059	2059	2059	N/A	1441	1628	mA
		XC6VLX240T	2478	2478	2478	N/A	1733	1957	mA
		XC6VLX365T	3001	3001	3001	N/A	2092	2363	mA
		XC6VLX550T <sup>(3)</sup>	N/A	4515	4515	N/A	3147	3555	mA
		XC6VLX760 <sup>(3)</sup>	N/A	5094	5094	N/A	3471	3921	mA
		XC6VSX315T	3476	3476	3476	N/A	2409	2721	mA
		XC6VSX475T <sup>(3)</sup>	N/A	5227	5227	N/A	3622	4091	mA
		XC6VHX250T	2906	2906	2906	N/A	N/A	N/A	mA
		XC6VHX255T	2746	2746	2746	N/A	N/A	N/A	mA
		XC6VHX380T <sup>(4)</sup>	4160	4160	4160	N/A	N/A	N/A	mA
		XC6VHX565T <sup>(5)</sup>	N/A	5207	5207	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1563	N/A	1563	N/A	1245	mA
		XQ6VLX240T	N/A	2478	N/A	2478	N/A	1957	mA
		XQ6VLX550T <sup>(7)</sup>	N/A	N/A	N/A	4515	N/A	3555	mA
		XQ6VSX315T	N/A	3476	N/A	3476	N/A	2721	mA
		XQ6VSX475T <sup>(7)</sup>	N/A	N/A	N/A	5227	N/A	4091	mA

## Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on sequence and ramp rate of the power supply.

The recommended power-on sequence for Virtex-6 devices is  $V_{CCINT}$ ,  $V_{CCAUX}$ , and  $V_{CCO}$  to meet the power-up current requirements listed in [Table 5](#).  $V_{CCINT}$  can be powered up or down at any time, but power up current specifications can vary from [Table 5](#). The device will have no physical damage or reliability concerns if  $V_{CCINT}$ ,  $V_{CCAUX}$ , and  $V_{CCO}$  sequence cannot be followed.

If the recommended power-up sequence cannot be followed and the I/Os must remain 3-stated throughout configuration, then  $V_{CCAUX}$  must be powered prior to  $V_{CCO}$  or  $V_{CCAUX}$  and  $V_{CCO}$  must be powered by the same supply. Similarly, for power-down, the reverse  $V_{CCAUX}$  and  $V_{CCO}$  sequence is recommended if the I/Os are to remain 3-stated.

The GTH transceiver supplies must be powered using a MGTHAVCC, MGTHAVCCR, MGTHAVCCPLL, and MGTHAVTT sequence. There are no sequencing requirement for these supplies with respect to the other FPGA supply voltages. For more detail see [Table 27: GTH Transceiver Power Supply Sequencing](#). There are no sequencing requirements for the GTX transceivers power supplies.

[Table 5](#) shows the minimum current, in addition to  $I_{CCQ}$ , that are required by Virtex-6 devices for proper power-on and configuration. If the current minimums shown in [Table 4](#) and [Table 5](#) are met, the device powers on after all three supplies have passed through their power-on reset threshold voltages. The FPGA must be configured after applying  $V_{CCINT}$ ,  $V_{CCAUX}$ , and  $V_{CCO}$  for the appropriate configuration banks. Once initialized and configured, use the XPE tools to estimate current drain on these supplies.

**Table 5: Power-On Current for Virtex-6 Devices**

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	$I_{CCOMIN}$	Units
	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	
XC6VLX75T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX130T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 10$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX195T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX240T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX365T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX550T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VLX760	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX315T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VSX475T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX250T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX255T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX380T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XC6VHX565T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX130T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX240T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VLX550T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 30 \text{ mA per bank}$	mA
XQ6VSX315T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA
XQ6VSX475T	See $I_{CCINTQ}$ in <a href="#">Table 4</a>	$I_{CCAUXQ} + 100$	$I_{CCOQ} + 40 \text{ mA per bank}$	mA

**Notes:**

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

Table 16: GTX Transceiver Quiescent Supply Current (per Lane) <sup>(1)(2)(3)</sup>

Symbol	Description	Typ <sup>(4)</sup>	Max	Units
IMGTAVTTQ	Quiescent MGTAVTT supply current for one GTX transceiver	0.9	Note 2	mA
IMGTAVCCQ	Quiescent MGTAVCC supply current for one GTX transceiver	3.5		mA

**Notes:**

1. Device powered and unconfigured.
2. Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.
3. GTX transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTX transceivers.
4. Typical values are specified at nominal voltage, 25°C.

**GTX Transceiver DC Input and Output Levels**

Table 17 summarizes the DC output specifications of the GTX transceivers in Virtex-6 FPGAs. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 17: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV <sub>PPIN</sub>	Differential peak-to-peak input voltage	External AC coupled ≤ 4.25 Gb/s	125	–	2000	mV
		External AC coupled > 4.25 Gb/s	175	–	2000	mV
V <sub>IN</sub>	Absolute input voltage	DC coupled MGTAVTT = 1.2V	–400	–	MGTAVTT	mV
V <sub>CMIN</sub>	Common mode input voltage	DC coupled MGTAVTT = 1.2V	–	2/3 MGTAVTT	–	mV
DV <sub>PPOUT</sub>	Differential peak-to-peak output voltage <sup>(1)</sup>	Transmitter output swing is set to maximum setting	–	–	1000	mV
V <sub>CMOUTDC</sub>	DC common mode output voltage.	Equation based	MGTAVTT – DV <sub>PPOUT</sub> /4			mV
R <sub>IN</sub>	Differential input resistance		80	100	130	Ω
R <sub>OUT</sub>	Differential output resistance		80	100	120	Ω
T <sub>OSKEW</sub>	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	8	ps
C <sub>EXT</sub>	Recommended external AC coupling capacitor <sup>(2)</sup>		–	100	–	nF

**Notes:**

1. The output swing and preemphasis levels are programmable using the attributes discussed in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

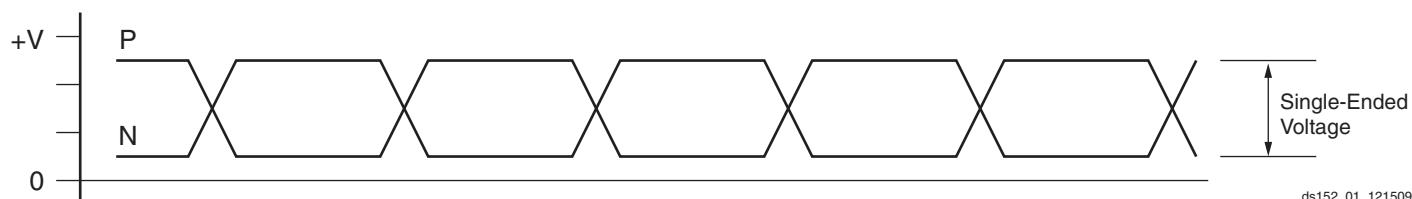
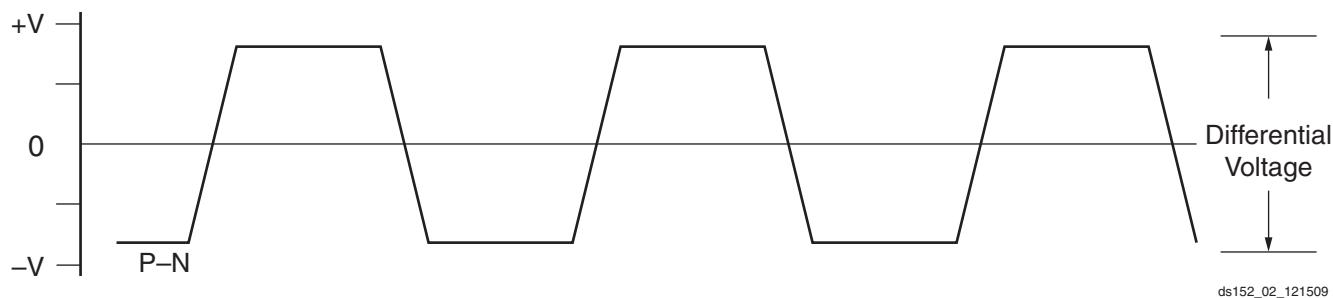


Figure 1: Single-Ended Peak-to-Peak Voltage



**Figure 2: Differential Peak-to-Peak Voltage**

Table 18 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

**Table 18: GTX Transceiver Clock DC Input Level Specification**

Symbol	DC Parameter	Min	Typ	Max	Units
$V_{IDIFF}$	Differential peak-to-peak input voltage	210	800	2000	mV
$R_{IN}$	Differential input resistance	90	100	130	$\Omega$
$C_{EXT}$	Required external AC coupling capacitor	–	100	–	nF

## GTX Transceiver Switching Characteristics

Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further information.

**Table 19: GTX Transceiver Performance**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXMAX}$	Maximum GTX transceiver data rate	6.6	6.6	5.0	5.0	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	3.3 <sup>(1)</sup>	3.3 <sup>(1)</sup>	2.7	2.7	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	1.2	1.2	GHz

### Notes:

- See Table 14 for MGTAVCC requirements when PLL frequency is greater than 2.7 GHz.

**Table 20: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	150	150	125	100	MHz

Table 21: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
$F_{GCLK}$	Reference clock frequency range		62.5	—	650	MHz
$T_{RCLK}$	Reference clock rise time	20% – 80%	—	200	—	ps
$T_{FCLK}$	Reference clock fall time	80% – 20%	—	200	—	ps
$T_{DCREF}$	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
$T_{LOCK}$	Clock recovery frequency acquisition time	Initial PLL lock	—	—	1	ms
$T_{PHASE}$	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	—	—	200	μs

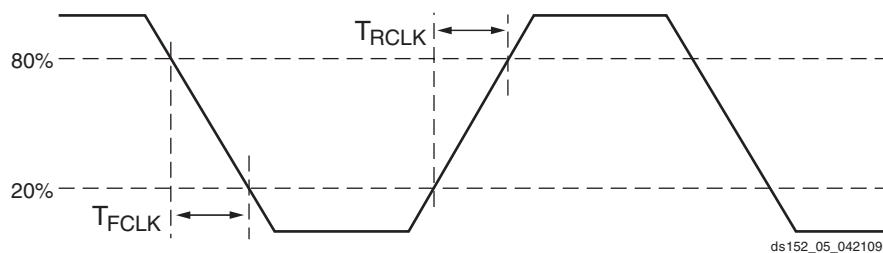


Figure 3: Reference Clock Timing Parameters

Table 22: GTX Transceiver User Clock Switching Characteristics<sup>(1)</sup>

Symbol	Description	Conditions	Speed Grade				Units
			-3	-2	-1	-1L	
$F_{TXOUT}$	TXOUTCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
$F_{RXREC}$	RXRECCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
$T_{RX}$	RXUSRCLK maximum frequency		412.5 <sup>(2)</sup>	412.5 <sup>(2)</sup>	312.5	250	MHz
$T_{RX2}$	RXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz
$T_{TX}$	TXUSRCLK maximum frequency		412.5 <sup>(3)</sup>	412.5 <sup>(3)</sup>	312.5	250	MHz
$T_{TX2}$	TXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz

**Notes:**

1. Clocking must be implemented as described in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#).
2. 406.25 MHz when the RX elastic buffer is bypassed.
3. 406.25 MHz when the TX buffer is bypassed.

Table 24: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
$F_{GTXRX}$	Serial data rate	RX oversampler not enabled	0.600	—	$F_{GTXMAX}$	Gb/s
		RX oversampler enabled	0.480	—	0.600	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	75	—	ns
$RX_{OOBVDP}$	OOB detect threshold peak-to-peak		60	—	150	mV
$RX_{SST}$	Receiver spread-spectrum tracking <sup>(1)</sup>	Modulated @ 33 KHz	-5000	—	0	ppm
$RX_{RL}$	Run length (CID)	Internal AC capacitor bypassed	—	—	512	UI
$RX_{PPMTOL}$	Data/REFCLK PPM offset tolerance	CDR 2 <sup>nd</sup> -order loop disabled	-200	—	200	ppm
		CDR 2 <sup>nd</sup> -order loop enabled	-2000	—	2000	ppm
<b>SJ Jitter Tolerance<sup>(2)</sup></b>						
$JT_{SJ}_{6.5}$	Sinusoidal Jitter <sup>(3)</sup>	6.5 Gb/s	0.44	—	—	UI
$JT_{SJ}_{5.0}$	Sinusoidal Jitter <sup>(3)</sup>	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ}_{4.25}$	Sinusoidal Jitter <sup>(3)</sup>	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ}_{3.75}$	Sinusoidal Jitter <sup>(3)</sup>	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ}_{3.125}$	Sinusoidal Jitter <sup>(3)</sup>	3.125 Gb/s	0.45	—	—	UI
$JT_{SJ}_{3.125L}$	Sinusoidal Jitter <sup>(3)</sup>	3.125 Gb/s <sup>(4)</sup>	0.45	—	—	UI
$JT_{SJ}_{2.5}$	Sinusoidal Jitter <sup>(3)</sup>	2.5 Gb/s <sup>(5)</sup>	0.5	—	—	UI
$JT_{SJ}_{1.25}$	Sinusoidal Jitter <sup>(3)</sup>	1.25 Gb/s <sup>(6)</sup>	0.5	—	—	UI
$JT_{SJ}_{600}$	Sinusoidal Jitter <sup>(3)</sup>	600 Mb/s	0.4	—	—	UI
$JT_{SJ}_{480}$	Sinusoidal Jitter <sup>(3)</sup>	480 Mb/s	0.4	—	—	UI
<b>SJ Jitter Tolerance with Stressed Eye<sup>(2)</sup></b>						
$JT_{TJSE}_{3.125}$	Total Jitter with Stressed Eye <sup>(7)</sup>	3.125 Gb/s	0.70	—	—	UI
		5.0 Gb/s	0.70	—	—	UI
$JT_{SJSE}_{3.125}$	Sinusoidal Jitter with Stressed Eye <sup>(7)</sup>	3.125 Gb/s	0.1	—	—	UI
		5.0 Gb/s	0.1	—	—	UI

**Notes:**

1. Using PLL\_RXDIVSEL\_OUT = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of  $1e^{-12}$ .
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.
7. Composite jitter with RX equalizer enabled. DFE disabled.

## Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:  
<http://www.xilinx.com/technology/protocols/pciexpress.htm>

**Table 39: Maximum Performance for PCI Express Designs**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F <sub>PIPECLK</sub>	Pipe clock maximum frequency	250	250	250	250	MHz
F <sub>USERCLK</sub>	User clock maximum frequency	500	500	250	250	MHz
F <sub>DRPCLK</sub>	DRP clock maximum frequency	250	250	250	250	MHz

## System Monitor Analog-to-Digital Converter Specification

**Table 40: Analog-to-Digital Specifications**

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$AV_{DD} = 2.5V \pm 5\%$ , $V_{REFP} = 1.25V$ , $V_{REFN} = 0V$ , ADCCLK = 5.2 MHz, $T_j = -55^{\circ}C$ to $125^{\circ}C$ M-Grade, Typical values at $T_j=+35^{\circ}C$						
<b>DC Accuracy:</b> All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	$\pm 1$	LSBs
Differential Nonlinearity	DNL	No missing codes ( $T_{MIN}$ to $T_{MAX}$ ) Guaranteed Monotonic	–	–	$\pm 0.9$	LSBs
Unipolar Offset Error <sup>(1)</sup>		Uncalibrated	–	$\pm 2$	$\pm 30$	LSBs
Bipolar Offset Error <sup>(1)</sup>		Uncalibrated measured in bipolar mode	–	$\pm 2$	$\pm 30$	LSBs
Gain Error		Uncalibrated - External Reference	–	$\pm 0.2$	$\pm 2$	%
		Uncalibrated - Internal Reference	–	$\pm 2$	–	%
Bipolar Gain Error <sup>(1)</sup>		Uncalibrated - External Reference	–	$\pm 0.2$	$\pm 2$	%
		Uncalibrated - Internal Reference	–	$\pm 2$	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	$\pm 10$	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	$\pm 20$	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	$\pm 1$	$\pm 2$	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	$\pm 0.01$	–	LSB/ $^{\circ}C$
DC Common-Mode Reject	CMRR <sub>DC</sub>	$V_N = V_{CM} = 0.5V \pm 0.5V$ , $V_P - V_N = 100mV$	–	70	–	dB
<b>Conversion Rate<sup>(2)</sup></b>						
Conversion Time - Continuous	t <sub>CONV</sub>	Number of CLK cycles	26	–	32	
Conversion Time - Event	t <sub>CONV</sub>	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t <sub>Acq</sub>	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

## Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label ([Advance](#), [Preliminary](#), [Production](#)). Any labeling discrepancies are corrected in subsequent speed specification releases.

**Table 43** lists the production released Virtex-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE® software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

**Table 43: Virtex-6 Device Production Software and Speed Specification Release**

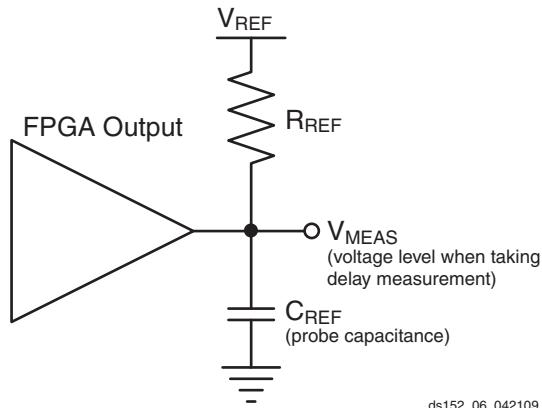
Device	Speed Grade Designations					
	-3	-2	-1	-1L		
XC6VLX75T	ISE 12.2 v1.08			ISE 12.3 v1.07 Patch		
XC6VLX130T	ISE 12.1 v1.06	ISE 11.5 v1.05 <sup>(2)</sup>	ISE 11.5 v1.05 <sup>(2)</sup>	ISE 12.2 v1.05		
XC6VLX195T	ISE 12.1 v1.06	ISE 12.1 v1.06	ISE 12.1 v1.06	ISE 12.2 v1.04		
XC6VLX240T	ISE 12.1 v1.06	ISE 11.4.1 v1.04 <sup>(2)</sup>	ISE 11.4.1 v1.04 <sup>(2)</sup>	ISE 12.2 v1.04		
XC6VLX365T	ISE 12.2 v1.08			ISE 12.2 v1.04		
XC6VLX550T	N/A	ISE 12.2 v1.07		ISE 12.2 v1.04		
XC6VLX760	N/A	ISE 12.2 v1.08		ISE 12.3 v1.07 Patch		
XC6VSX315T	ISE 12.2 v1.08	ISE 12.1 v1.06		ISE 12.3 v1.07 Patch		
XC6VSX475T	N/A	ISE 12.2 v1.08		ISE 12.3 v1.07 Patch		
XC6VHX250T	ISE 12.4 v1.10			N/A		
XC6VHX255T	ISE 13.1 v1.14 using the ISE 13.1 software update			N/A		
XC6VHX380T	ISE 12.4 v1.10			N/A		
XC6VHX565T	N/A	ISE 13.1 v1.14 using the ISE 13.1 software update		N/A		
XQ6VLX130T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VLX240T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VLX550T	N/A	N/A	ISE 13.3 v1.17 Patch	ISE 13.3 v1.10		
XQ6VSX315T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VSX475T	N/A	N/A	ISE 13.3 v1.17 Patch	ISE 13.3 v1.10		

**Notes:**

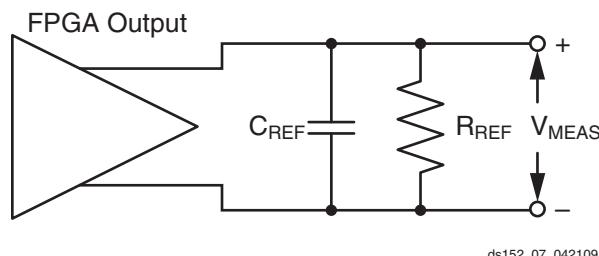
1. Blank entries indicate a device and/or speed grade in advance or preliminary status.
2. Designs utilizing the GTX transceivers must use the software version ISE 12.1 v1.06 or later.

## Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in [Figure 6](#) and [Figure 7](#).



**Figure 6: Single Ended Test Setup**



**Figure 7: Differential Test Setup**

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters  $V_{REF}$ ,  $R_{REF}$ ,  $C_{REF}$ , and  $V_{MEAS}$  fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from [Table 48](#).
2. Record the time to  $V_{MEAS}$ .
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to  $V_{MEAS}$ .
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

**Table 48: Output Delay Measurement Methodology**

Description	I/O Standard Attribute	$R_{REF}$ ( $\Omega$ )	$C_{REF}$ <sup>(1)</sup> (pF)	$V_{MEAS}$ (V)	$V_{REF}$ (V)
LVCMS, 2.5V	LVCMS25	1M	0	1.25	0
LVCMS, 1.8V	LVCMS18	1M	0	0.9	0
LVCMS, 1.5V	LVCMS15	1M	0	0.75	0
LVCMS, 1.2V	LVCMS12	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	$V_{REF}$	0.75
HSTL, Class II	HSTL_II	25	0	$V_{REF}$	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	$V_{REF}$	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	$V_{REF}$	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	$V_{REF}$	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	$V_{REF}$	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	$V_{REF}$	1.25
SSTL, Class II, 2.5V	SSTL2_II	25	0	$V_{REF}$	1.25
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	100	0	0 <sup>(2)</sup>	1.2
LVDSEXT (LVDS Extended Mode), 2.5V	LVDS_25	100	0	0 <sup>(2)</sup>	1.2
BLVDS (Bus LVDS), 2.5V	BLVDS_25	100	0	0 <sup>(2)</sup>	0

Table 50: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
<b>Setup/Hold</b>							
T <sub>DCK/T<sub>O</sub>CKD</sub>	D1/D2 pins Setup/Hold with respect to CLK	0.45/ -0.08	0.50/ -0.08	0.54/ -0.08	0.54/ -0.08	0.69/ -0.11	ns
T <sub>O</sub> OCECK/T <sub>O</sub> CKOCE	OCE pin Setup/Hold with respect to CLK	0.17/ -0.03	0.20/ -0.03	0.22/ -0.03	0.27/ -0.05	0.27/ -0.04	ns
T <sub>S</sub> SRCK/T <sub>O</sub> CKSR	SR pin Setup/Hold with respect to CLK	0.59/ -0.24	0.62/ -0.24	0.54/ -0.08	0.54/ -0.08	0.79/ -0.35	ns
T <sub>T</sub> TCK/T <sub>O</sub> CKT	T1/T2 pins Setup/Hold with respect to CLK	0.44/ -0.07	0.51/ -0.07	0.56/ -0.07	0.60/ -0.10	0.68/ -0.13	ns
T <sub>T</sub> TCECK/T <sub>O</sub> CKTCE	TCE pin Setup/Hold with respect to CLK	0.15/ -0.04	0.19/ -0.04	0.21/ -0.04	0.27/ -0.05	0.29/ -0.05	ns
<b>Combinatorial</b>							
T <sub>D</sub> OQ	D1 to OQ out or T1 to TQ out	0.78	0.87	1.01	1.01	1.15	ns
<b>Sequential Delays</b>							
T <sub>O</sub> CKQ	CLK to OQ/TQ out	0.54	0.61	0.71	0.71	0.80	ns
T <sub>R</sub> Q	SR pin to OQ/TQ out	0.80	0.90	1.05	1.05	1.19	ns
T <sub>G</sub> SRQ	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	10.51	ns
<b>Set/Reset</b>							
T <sub>R</sub> PW	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.20	1.30	ns, Min

Table 57: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>RCKC_WE</sub> /T <sub>RCKC_WREN</sub>	Write Enable (WE) input (Block RAM only)	0.44/ 0.19	0.47/ 0.25	0.52/ 0.35	0.67/ 0.24	ns, Min
T <sub>RCKC_WREN</sub> /T <sub>RCKC_RDEN</sub>	WREN FIFO inputs	0.47/ 0.26	0.50/ 0.27	0.55/ 0.30	0.68/ 0.31	ns, Min
T <sub>RCKC_RDEN</sub> /T <sub>RCKC_WREN</sub>	RDEN FIFO inputs	0.46/ 0.26	0.50/ 0.27	0.55/ 0.30	0.67/ 0.31	ns, Min
<b>Reset Delays</b>						
T <sub>RCO_FLAGS</sub>	Reset RST to FIFO Flags/Pointers <sup>(10)</sup>	0.90	0.98	1.10	1.23	ns, Max
T <sub>RCKC_RSTREG</sub> /T <sub>RCKC_RSTREG</sub>	FIFO reset timing <sup>(11)</sup>	0.22/ 0.23	0.24/ 0.24	0.28/ 0.26	0.31/ 0.27	ns, Min
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	Block RAM in TDP and SDP modes (Write First and No Change modes)	600	540	450	340	MHz
	Block RAM (Read First mode)	525	475	400	275	MHz
	Block RAM (SDP mode) <sup>(12)</sup>	525	475	400	275	MHz
F <sub>MAX_CASCADE</sub>	Block RAM Cascade (Write First and No Change modes)	550	490	400	300	MHz
	Block RAM Cascade (Read First mode)	475	425	350	235	MHz
F <sub>MAX_FIFO</sub>	FIFO in all modes	600	540	450	340	MHz
F <sub>MAX_ECC</sub>	Block RAM and FIFO in ECC configuration	450	400	325	250	MHz

**Notes:**

1. TRACE will report all of these parameters as T<sub>RCKO\_DO</sub>.
2. T<sub>RCKO\_DOR</sub> includes T<sub>RCKO\_DOW</sub>, T<sub>RCKO\_DOPR</sub>, and T<sub>RCKO\_DOPW</sub> as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO\_REG = 0.
4. T<sub>RCKO\_DO</sub> includes T<sub>RCKO\_DOP</sub> as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO\_REG = 1.
6. T<sub>RCKO\_FLAGS</sub> includes the following parameters: T<sub>RCKO\_AEMPTY</sub>, T<sub>RCKO\_AFULL</sub>, T<sub>RCKO\_EMPTY</sub>, T<sub>RCKO\_FULL</sub>, T<sub>RCKO\_RDERR</sub>, T<sub>RCKO\_WRERR</sub>.
7. T<sub>RCKO\_POINTERS</sub> includes both T<sub>RCKO\_RDCOUNT</sub> and T<sub>RCKO\_WRCOUNT</sub>.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. T<sub>RCKO\_DI</sub> includes both A and B inputs as well as the parity inputs of A and B.
10. T<sub>RCO\_FLAGS</sub> includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. The FIFO reset must be asserted for at least three positive clock edges.
12. When using ISE software v12.4 or later, if the RDADDR\_COLLISION\_HWCONFIG attribute is set to PERFORMANCE or the block RAM is in single-port operation, then the faster F<sub>MAX</sub> for WRITE\_FIRST/NO\_CHANGE modes apply.

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
T <sub>DSPDCK_RSTP_PREG</sub> / T <sub>DSPCKD_RSTP_PREG</sub>	RSTP input to P register CLK	0.26/ 0.04	0.30/ 0.04	0.35/ 0.05	0.35/ 0.05	0.43/ 0.06	ns
<b>Combinatorial Delays from Input Pins to Output Pins</b>							
T <sub>DSPDO_{A, B}_{P, CARRYOUT}_MULT</sub>	{A, B} input to {P, CARRYOUT} output using multiplier	3.76	4.29	5.08	5.08	5.87	ns
T <sub>DSPDO_D_{P, CARRYOUT}_MULT</sub>	D input to {P, CARRYOUT} output using multiplier	3.57	4.07	4.82	4.82	5.57	ns
T <sub>DSPDO_{A, B}_{P, CARRYOUT}</sub>	{A, B} input to {P, CARRYOUT} output not using multiplier	1.55	1.76	2.07	2.07	2.41	ns
T <sub>DSPDO_{C, CARRYIN}_{P, CARRYOUT}</sub>	{C, CARRYIN} input to {P, CARRYOUT} output	1.38	1.56	1.83	1.83	2.13	ns
<b>Combinatorial Delays from Input Pins to Cascading Output Pins</b>							
T <sub>DSPDO_{A; B}_{ACOUT; BCOUT}</sub>	{A, B} input to {ACOUT, BCOUT} output	0.49	0.56	0.65	0.65	0.73	ns
T <sub>DSPDO_{A, B}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT</sub>	{A, B} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.87	4.42	5.24	5.24	6.09	ns
T <sub>DSPDO_D_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT</sub>	D input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.66	4.17	4.94	4.94	5.76	ns
T <sub>DSPDO_{A, B}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}</sub>	{A, B} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.64	1.86	2.19	2.19	2.60	ns
T <sub>DSPDO_{C, CARRYIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}</sub>	{C, CARRYIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.46	1.66	1.95	1.95	2.32	ns
<b>Combinatorial Delays from Cascading Input Pins to All Output Pins</b>							
T <sub>DSPDO_{ACIN, BCIN}_{P, CARRYOUT}_MULT</sub>	{ACIN, BCIN} input to {P, CARRYOUT} output using multiplier	3.67	4.19	4.97	4.97	5.75	ns
T <sub>DSPDO_{ACIN, BCIN}_{P, CARRYOUT}</sub>	{ACIN, BCIN} input to {P, CARRYOUT} output not using multiplier	1.43	1.63	1.92	1.92	2.25	ns
T <sub>DSPDO_{ACIN; BCIN}_{ACOUT; BCOUT}</sub>	{ACIN, BCIN} input to {ACOUT, BCOUT} output	0.36	0.42	0.49	0.49	0.56	ns
T <sub>DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MULT</sub>	{ACIN, BCIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.76	4.29	5.10	5.10	5.94	ns
T <sub>DSPDO_{ACIN, BCIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}</sub>	{ACIN, BCIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.52	1.73	2.05	2.05	2.44	ns
T <sub>DSPDO_{PCIN, CARRYCASIN, MULTSIGNIN}_{P, CARRYOUT}</sub>	{PCIN, CARRYCASIN, MULTSIGNIN} input to {P, CARRYOUT} output	1.19	1.35	1.60	1.60	1.87	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
T <sub>DSPDO_{PCIN, CARRYCASCIN, MULTSIGNIN}_{PCOUT, CARRYCASOUT, MULTSIGNOUT}</sub>	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.28	1.46	1.72	1.72	2.06	ns
<b>Clock to Outs from Output Register Clock to Output Pins</b>							
T <sub>DSPCKO_{P, CARRYOUT}_PREG</sub>	CLK (PREG) to {P, CARRYOUT} output	0.38	0.43	0.50	0.50	0.57	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_PREG</sub>	CLK (PREG) to {CARRYCASOUT, PCOUT, MULTSIGNOUT} output	0.50	0.56	0.66	0.66	0.76	ns
<b>Clock to Outs from Pipeline Register Clock to Output Pins</b>							
T <sub>DSPCKO_{P, CARRYOUT}_MREG</sub>	CLK (MREG) to {P, CARRYOUT} output	1.72	1.96	2.30	2.30	2.69	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_MREG</sub>	CLK (MREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.81	2.06	2.43	2.43	2.88	ns
T <sub>DSPCKO_{P, CARRYOUT}_ADREG_MULT</sub>	CLK (ADREG) to {P, CARRYOUT} output	2.79	3.16	3.72	3.72	4.32	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_ADREG_MULT</sub>	CLK (ADREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	2.87	3.26	3.84	3.84	4.51	ns
<b>Clock to Outs from Input Register Clock to Output Pins</b>							
T <sub>DSPCKO_{P, CARRYOUT}_{AREG, BREG}_MULT</sub>	CLK (AREG, BREG) to {P, CARRYOUT} output using multiplier	3.97	4.52	5.36	5.36	6.20	ns
T <sub>DSPCKO_{P, CARRYOUT}_{AREG, BREG}</sub>	CLK (AREG, BREG) to {P, CARRYOUT} output not using multiplier	1.70	1.93	2.27	2.27	2.65	ns
T <sub>DSPCKO_{P, CARRYOUT}_CREG</sub>	CLK (CREG) to {P, CARRYOUT} output	1.70	1.93	2.27	2.27	2.80	ns
T <sub>DSPCKO_{P, CARRYOUT}_DREG_MULT</sub>	CLK (DREG) to {P, CARRYOUT} output	3.89	4.44	5.25	5.25	6.07	ns
<b>Clock to Outs from Input Register Clock to Cascading Output Pins</b>							
T <sub>DSPCKO_{ACOUT; BCOUT}_{AREG; BREG}</sub>	CLK (AREG, BREG) to {P, CARRYOUT} output	0.66	0.76	0.89	0.89	1.01	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}_MULT</sub>	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	4.05	4.63	5.49	5.49	6.39	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_{AREG, BREG}</sub>	CLK (AREG, BREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output not using multiplier	1.79	2.03	2.40	2.40	2.84	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_DREG_MULT</sub>	CLK (DREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output using multiplier	3.98	4.54	5.38	5.38	6.26	ns
T <sub>DSPCKO_{PCOUT, CARRYCASOUT, MULTSIGNOUT}_CREG</sub>	CLK (CREG) to {PCOUT, CARRYCASOUT, MULTSIGNOUT} output	1.78	2.03	2.40	2.40	2.99	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$T_{SMCKBY}$	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
$F_{SMCCK}$	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
$F_{RBCK}$	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
<b>Boundary-Scan Port Timing Specifications</b>						
$T_{TAP TCK}/T_{TCK TAP}$	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
$T_{TCK TDO}$	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
$F_{TCK}$	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
$F_{TCKB\_MIN}$	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
$F_{TCKB}$	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
<b>BPI Master Flash Mode Programming Switching</b>						
$T_{BPICCO}^{(2)}$	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
$T_{BPIDCC}/T_{BPICCD}$	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
$T_{INITADDR}$	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
<b>SPI Master Flash Mode Programming Switching</b>						
$T_{SPIDCC}/T_{SPIDCCD}$	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
$T_{SPICCM}$	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
$T_{SPICCFc}$	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
$T_{FSINIT}/T_{FSINITH}$	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	μs
<b>CCLK Output (Master Modes)</b>						
$T_{MCCKL}$	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
$T_{MCCKH}$	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
<b>CCLK Input (Slave Modes)</b>						
$T_{SCCKL}$	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
$T_{SCCKH}$	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
<b>Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK</b>						
$F_{DCK}$	Maximum frequency for DCLK	200	200	200	200	MHz
$T_{MMCMDCK\_DADDR}/T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>MMCMDCK_DI</sub> / T <sub>MMCMCKD_DI</sub>	DI Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T <sub>MMCMDCK_DEN</sub> / T <sub>MMCMCKD_DEN</sub>	DEN Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T <sub>MMCMDCK_DWE</sub> / T <sub>MMCMCKD_DWE</sub>	DWE Setup/Hold time	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns
T <sub>MMCMCKO_DO</sub>	CLK to out of DO <sup>(3)</sup>	2.60	3.02	3.64	3.68	ns
T <sub>MMCMCKO_DRDY</sub>	CLK to out of DRDY	0.32	0.34	0.38	0.38	ns

**Notes:**

1. To support longer delays in configuration, use the design solutions described in [UG360: Virtex-6 FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
3. DO will hold until next DRP operation.

## Clock Buffers and Networks

Table 60: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Devices	Speed Grade				Units
			-3	-2	-1	-1L	
T <sub>BCCCK_CE</sub> / T <sub>BCCKC_CE</sub> <sup>(1)</sup>	CE pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
T <sub>BCCCK_S</sub> / T <sub>BCCKC_S</sub> <sup>(1)</sup>	S pins Setup/Hold	All	0.11/ 0.00	0.13/ 0.00	0.16/ 0.00	0.13/ 0.00	ns
T <sub>BGCKO_O</sub> <sup>(2)</sup>	BUFGCTRL delay from I0/I1 to O	All	0.07	0.08	0.10	0.10	ns
<b>Maximum Frequency</b>							
F <sub>MAX</sub>	Global clock tree (BUFG)	All except LX760	800	750	700	667	MHz
		LX760	N/A	700	700	667	MHz

**Notes:**

1. T<sub>BCCCK\_CE</sub> and T<sub>BCCKC\_CE</sub> must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX\_VIRTEX4 primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T<sub>BGCKO\_O</sub> (BUFG delay from I0 to O) values are the same as T<sub>BGCKO\_O</sub> values.

Table 61: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>BLOCKO_O</sub>	Clock to out delay from I to O	0.14	0.16	0.18	0.21	ns
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	I/O clock tree (BUFIO)	800	800	710	710	MHz

Table 62: Regional Clock Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>BRCKO_O</sub>	Clock to out delay from I to O	0.56	0.62	0.73	0.82	ns
T <sub>BRCKO_O_BYP</sub>	Clock to out delay from I to O with Divide Bypass attribute set	0.28	0.31	0.36	0.41	ns

Table 62: Regional Clock Switching Characteristics (BUFR) (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>BRDO_O</sub>	Propagation delay from CLR to O	0.69	0.74	0.80	1.12	ns
<b>Maximum Frequency</b>						
F <sub>MAX</sub> <sup>(1)</sup>	Regional clock tree (BUFR)	500	420	300	300	MHz

**Notes:**

1. The maximum input frequency to the BUFR is the BUFIo F<sub>MAX</sub> frequency.

Table 63: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T <sub>BHCKO_O</sub>	BUFH delay from I to O	0.10	0.11	0.13	0.15	ns
T <sub>BHCKC_CE</sub> /T <sub>BHCKC_CE</sub>	CE pin Setup and Hold	0.04/ 0.04	0.04/ 0.04	0.05/ 0.05	0.04/ 0.04	ns
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	Horizontal clock buffer (BUFH)	800	750	700	667	MHz

**MMCM Switching Characteristics**

Table 64: MMCM Specification

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F <sub>INMAX</sub>	Maximum Input Clock Frequency <sup>(1)</sup>	800	750	700	700	MHz
F <sub>INMIN</sub>	Minimum Input Clock Frequency	10	10	10	10	MHz
F <sub>INJITTER</sub>	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
F <sub>INDUTY</sub> <sup>(2)</sup>	Allowable Input Duty Cycle: 10—49 MHz	25/75				%
	Allowable Input Duty Cycle: 50—199 MHz	30/70				%
	Allowable Input Duty Cycle: 200—399 MHz	35/65				%
	Allowable Input Duty Cycle: 400—499 MHz	40/60				%
	Allowable Input Duty Cycle: >500 MHz	45/55				%
F <sub>MIN_PSCLK</sub>	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
F <sub>MAX_PSCLK</sub>	Maximum Dynamic Phase Shift Clock Frequency	550	500	450	450	MHz
F <sub>VCOMIN</sub>	Minimum MMCM VCO Frequency	600	600	600	600	MHz
F <sub>VCOMAX</sub>	Maximum MMCM VCO Frequency	1600	1440	1200	1200	MHz
F <sub>BANDWIDTH</sub>	Low MMCM Bandwidth at Typical <sup>(3)</sup>	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical <sup>(3)</sup>	4.00	4.00	4.00	4.00	MHz
T <sub>STATPHAOFFSET</sub>	Static Phase Offset of the MMCM Outputs <sup>(4)</sup>	0.12	0.12	0.12	0.12	ns
T <sub>OUTJITTER</sub>	MMCM Output Jitter <sup>(5)</sup>	Note 3				
T <sub>OUTDUTY</sub>	MMCM Output Clock Duty Cycle Precision <sup>(6)</sup>	0.15	0.20	0.20	0.20	ns
T <sub>LOCKMAX</sub>	MMCM Maximum Lock Time	100	100	100	100	μs
F <sub>OUTMAX</sub>	MMCM Maximum Output Frequency	800	750	700	700	MHz
F <sub>OUTMIN</sub>	MMCM Minimum Output Frequency <sup>(7)(8)</sup>	4.69	4.69	4.69	4.69	MHz
T <sub>EXTFDVAR</sub>	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				

Table 66: Global Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
T <sub>C</sub> KOFMMCMGC	Global Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.34	2.50	2.77	2.85	ns
		XC6VLX130T	2.35	2.51	2.78	2.87	ns
		XC6VLX195T	2.36	2.52	2.79	2.88	ns
		XC6VLX240T	2.36	2.52	2.79	2.88	ns
		XC6VLX365T	2.37	2.53	2.79	2.89	ns
		XC6VLX550T	N/A	2.55	2.82	2.93	ns
		XC6VLX760	N/A	2.54	2.82	2.92	ns
		XC6VSX315T	2.35	2.51	2.79	2.87	ns
		XC6VSX475T	N/A	2.43	2.70	2.79	ns
		XC6VHX250T	2.36	2.53	2.80	N/A	ns
		XC6VHX255T	2.46	2.63	2.91	N/A	ns
		XC6VHX380T	2.39	2.59	2.83	N/A	ns
		XC6VHX565T	N/A	2.54	2.81	N/A	ns
		XQ6VLX130T	N/A	2.51	2.78	2.87	ns
		XQ6VLX240T	N/A	2.52	2.79	2.88	ns
		XQ6VLX550T	N/A	N/A	2.82	2.93	ns
		XQ6VSX315T	N/A	2.51	2.79	2.87	ns
		XQ6VSX475T	N/A	N/A	2.70	2.79	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Table 67: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Clock-capable Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> MMCM.							
TICKOFMMCMCC	Clock-capable Clock Input and OUTFF <i>with</i> MMCM	XC6VLX75T	2.22	2.38	2.63	2.72	ns
		XC6VLX130T	2.24	2.39	2.65	2.74	ns
		XC6VLX195T	2.24	2.40	2.65	2.75	ns
		XC6VLX240T	2.24	2.40	2.65	2.75	ns
		XC6VLX365T	2.25	2.42	2.65	2.76	ns
		XC6VLX550T	N/A	2.43	2.68	2.80	ns
		XC6VLX760	N/A	2.42	2.69	2.79	ns
		XC6VSX315T	2.23	2.38	2.65	2.73	ns
		XC6VSX475T	N/A	2.30	2.57	2.66	ns
		XC6VHX250T	2.25	2.41	2.67	N/A	ns
		XC6VHX255T	2.35	2.51	2.78	N/A	ns
		XC6VHX380T	2.27	2.43	2.69	N/A	ns
		XC6VHX565T	N/A	2.41	2.68	N/A	ns
		XQ6VLX130T	N/A	2.39	2.65	2.74	ns
		XQ6VLX240T	N/A	2.40	2.65	2.75	ns
		XQ6VLX550T	N/A	N/A	2.68	2.80	ns
		XQ6VSX315T	N/A	2.38	2.65	2.73	ns
		XQ6VSX475T	N/A	N/A	2.57	2.66	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

Date	Version	Description of Revisions
01/18/10	2.1	Changed absolute maximum ratings for both $V_{IN}$ and $V_{TS}$ in <a href="#">Table 1</a> . Added data to <a href="#">Table 3</a> . Added data to <a href="#">Table 5</a> . Updated SSTL15 in <a href="#">Table 7</a> . Updated $V_{OCM}$ and $V_{OD}$ values in <a href="#">Table 8</a> . Added eFUSE endurance <a href="#">Table 12</a> . Added values to $V_{MGTREFCLK}$ and $V_{IN}$ in <a href="#">Table 13, page 11</a> . Added values and updated tables in the <a href="#">GTX Transceiver Specifications</a> and <a href="#">GTH Transceiver Specifications</a> sections. Added <a href="#">Table 27</a> and <a href="#">Figure 4</a> . Revised parameters and values in <a href="#">Table 39</a> . Updated <a href="#">Table 40, page 23</a> . Added data to <a href="#">Table 41</a> . Updated speed specification to v1.04 with appropriate changes to <a href="#">Table 42</a> and <a href="#">Table 43</a> including production release of the XC6VLX240T for -1 and -2 speed grades. Speed specification changes and numerous updates also made to <a href="#">Table 44</a> , and <a href="#">Table 49</a> through <a href="#">Table 71</a> . Added data to <a href="#">Table 73</a> and <a href="#">Table 74</a> .
02/09/10	2.2	Revised description of $C_{IN}$ in <a href="#">Table 3</a> . Clarified values in <a href="#">Table 5</a> . Fixed SDR LVDS unit error in <a href="#">Table 41</a> .
04/12/10	2.3	Added note 3 and update value of $n$ in <a href="#">Table 3</a> . Clarified simultaneous power-down in <a href="#">Power-On Power Supply Requirements</a> . Updated external reference junction temperatures in <a href="#">Table 40, Analog-to-Digital Specifications</a> . Updated speed specification to v1.05 with appropriate changes to <a href="#">Table 42</a> and <a href="#">Table 43</a> including production release of the XC6VLX130T for -1 and -2 speed grades. Fixed note 4 in <a href="#">Table 48</a> . Increased the -2 specification for $F_{IDELAYCTRL\_REF}$ and clarified units for $T_{IDELAYPAT\_JIT}$ in <a href="#">Table 53</a> . Added note 1 to <a href="#">Table 62</a> .
05/11/10	2.4	Updated $F_{RXREC}$ in <a href="#">Table 22</a> . Revised $F_{IDELAYCTRL\_REF}$ in <a href="#">Table 53</a> . Removed $T_{RCKO\_PARITY\_ECC}$ : Clock CLK to ECCPARITY in standard ECC mode row in <a href="#">Table 57</a> . Added XC6VLX130T values to <a href="#">Table 72</a> .
05/26/10	2.5	Added XC6VLX195T data to <a href="#">Table 5</a> . Updated values in <a href="#">Table 22</a> including adding note 2 and note 3. Updated speed specification to v1.06 with appropriate changes to <a href="#">Table 42</a> and <a href="#">Table 43</a> including production release of the XC6VLX195T for -1 and -2 speed grades. Added XC6VLX195T values to <a href="#">Table 72</a> .
07/16/10	2.6	Changed <a href="#">Table 42</a> and <a href="#">Table 43</a> to production status on the -3 speed grade XC6VLX130T, XC6VLX195T, and XC6VLX240T devices. Added XC6VHX250T data to <a href="#">Table 4</a> and <a href="#">Table 72</a> . Added Note 6 to <a href="#">Table 64</a> .
07/23/10	2.7	Changed <a href="#">Table 42</a> and <a href="#">Table 43</a> to production status on the XC6VLX75T, XC6VLX365T, XC6VLX550T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.2 software with speed specification v1.08. Updated $V_{CMOUTDC}$ equation to $MGTAVTT - D_{VPPOUT}/4$ in <a href="#">Table 17</a> . Updated some -3, -2, -1 specifications in <a href="#">Table 65</a> through <a href="#">Table 72</a> . Added and updated -1L specifications to <a href="#">Table 41</a> and for most switching characteristics tables.
07/30/10	2.8	Changed <a href="#">Table 42</a> and <a href="#">Table 43</a> to production status on the -1L speed grade for the XC6VLX130T, XC6VLX195T, XC6VLX240T, XC6VLX365T, and XC6VLX550T devices using ISE 12.2 software with current speed specifications. Also updated the speed specifications for XC6VLX75T, XC6VLX550T, and XC6VSX315T. Updated $V_{CCINT}$ specifications for -1L speed grade industrial temperature range devices in <a href="#">Table 2</a> .
09/20/10	2.9	In <a href="#">Table 32</a> , changed $F_{GPLLMAX}$ specification in -3 column from 5.951 to 5.591. In <a href="#">Table 40</a> , changed $F_{MAX}$ for the DCLK from 250 MHz to 80 MHz.
10/18/10	2.10	The specification change in version 2.9, <a href="#">Table 40</a> is described in <a href="#">XCN10032, Virtex-6 FPGA: GTX Transceiver User Guide, Family Data Sheet (SYSMON DCLK), and JTAG ID Changes</a> . In this version (2.10), -1L(I) data is added to <a href="#">Table 4</a> and clarified in Note 2. Changed <a href="#">Table 42</a> and <a href="#">Table 43</a> to production status on the -1L speed grade XC6VLX75T, XC6VLX760, XC6VSX315T, and XC6VSX475T devices using ISE 12.3 software with current speed specifications. Revised the XC6VLX760 -1L speed specification for $T_{PHMMCMB}$ in <a href="#">Table 69</a> and $T_{PHMMCMB}$ in <a href="#">Table 70</a> .
01/17/11	2.11	Changed in <a href="#">Table 42</a> and <a href="#">Table 43</a> to production status on the XC6VHX250T devices using ISE 12.4 software with current speed specifications. Added industrial temperature range ( $T_i$ ) recommended specifications to <a href="#">Table 2</a> ; including specific ranges for the -2I XC6VSX475T, XC6VLX550T, XC6VLX760, and XC6VHX565T devices. Added note 3 to <a href="#">Table 36</a> and maximum total jitter values. Added note 4 to <a href="#">Table 37</a> and maximum sinusoidal jitter values. Added note 2 to <a href="#">Table 43</a> . Revised $F_{MAX}$ descriptions in <a href="#">Table 57</a> and added note 12. Added note 8 to $F_{PFDMIN}$ in <a href="#">Table 64</a> . The following revisions are due to specification changes as described in <a href="#">XCN11009, Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates</a> . In <a href="#">Table 59: Configuration Switching Characteristics, page 49</a> , revised -1L specifications for $T_{POR}$ , $F_{MCCK}$ , $F_{MCCKTOL}$ , $T_{SMCSCCK}$ , $T_{SMCCCKW}$ , $F_{RBCK}$ , $F_{TCK}$ , $F_{TCKB}$ , $T_{MCCKL}$ , and $T_{MCCKH}$ . In <a href="#">Table 64: MMCM Specification</a> , added bandwidth settings to $F_{PFDMIN}$ and added note 1.